



BSI Standards Publication

Nanomanufacturing — Key control characteristics

Part 6-23: Graphene-related products — Sheet resistance, carrier density, carrier mobility: Hall bar method

National foreword

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TECHNICAL SPECIFICATION

**Nanomanufacturing - Key control characteristics -
Part 6-23: Graphene-related products - Sheet resistance, carrier density, carrier
mobility: Hall bar method**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

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The language used for the development of this Technical Specification is English.

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